

10010591-1

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**Patent Application for:**

**Controlling Electronics Across an RF Barrier Using a Serial Interface Bus**

SEARCHED - SERIALIZED

**Inventors:** Bryan D. Boswell  
Richard E. Warren  
Gregory E. Brandes

**Docket Number:** 10010591-1

1

2

3

4

## Controlling Electronics Across an RF Barrier Using a Serial Interface

6

7

8

## TECHNICAL FIELD

10

11 This invention relates generally to the field of radio frequency (RF) fixture  
12 devices, and more specifically to a method of controlling electronics across an  
13 RF barrier.

14

## BACKGROUND OF THE INVENTION

16

RF enclosures may be used in a variety of test and measurement applications when the amount of RF radiation that impacts a device under test (DUT) must be carefully controlled. Specific examples include prototype testing and production testing of cellular telephones, portable computers, pagers, and other small electronic devices. Often RF enclosures are used in automated or semi-automated environments in which machines are used to place the DUT inside the RF enclosure. In these types of test environments, it is desirable to be able to evaluate the functionality and correct operation of the DUT while the DUT is within the RF enclosure. The use of electronics circuitry and software may be used to apply specific test resources to the DUT and measure the responses. In most applications, the electronics circuitry and software is located both internal and external to the RF enclosure. However, placing high speed electronics within the RF enclosure reduces the RF isolation and generates spurious noise, therefore degrading the testing accuracy. The proximity of the electronics to the DUT also influences the measurement accuracy. Thus, in test and measurement situations involving an RF enclosure, there are often two competing design considerations:

100010591-1  
PDF EDITION

10010591-1

1 Including more sophisticated electronic components within an RF enclosure  
2 allows more accurate and more comprehensive test procedures to be  
3 executed. However from the point of view of RF isolation and noise reduction  
4 , fewer electronics components create smaller amounts of spurious RF energy  
5 that leads to improved RF measurements. These competing considerations  
6 must both be addressed when designing RF test and measurement systems  
7 that incorporate RF enclosures.

8

9 A further issue when electronics components are used within an RF enclosure  
10 is the complexity of the interface between the electronics inside the RF  
11 enclosure and the electronics outside the RF enclosure. As the number of  
12 communication paths that cross the RF interface increase, so does the  
13 amount of RF noise generated by each path. Thus, a secondary design  
14 consideration is the method of controlling the electronics path across an RF  
15 barrier of an RF enclosure.

16

17 There are many different methods of controlling electronics across an RF  
18 barrier of an RF enclosure. The RF enclosure may be used to test and  
19 prototype electronics devices, such as cell phones, personal digital assistants  
20 (PDAs), and other similar electronics. Most methods of controlling electronics  
21 across an RF barrier use electrical signals propagating through a filtered  
22 connector as the primary transport mechanism. These electrical signals can  
23 carry data reads and data writes to and from the electronics within an RF  
24 enclosure. Most of these methods may be classified into one of three basic  
25 types: direct drive, wide parallel, and command serial.

26

27 A direct drive control method consists of providing dedicated electrical  
28 resources outside of the RF enclosure that pass through the filtered  
29 connector(s) for each element being controlled. An example of this type of

10010591-1

1 control method would be to generate relay coil drive signals outside the RF  
2 cavity and pass each of these drive lines through the filtered connectors to  
3 relays inside the cavity. This method requires an individual control line that  
4 passes through the filtered connector for each resource being controlled. It is  
5 desirable to limit the number of control lines passing through the filtered  
6 connectors since these filtered connectors are very expensive (approximately  
7 \$2.00/line) and the effective RF isolation of the structure degrades with the  
8 number of signals passing through the filtered connectors. A direct drive  
9 scheme is also not very flexible or expandable.

10

11 A wide parallel control method consists of a conventional address, data, and  
12 control scheme in which all signals must pass through the filtered  
13 connectors(s) to register based electronics inside the RF cavity. This method  
14 often requires a large number of signals passing through the filtered  
15 connectors. A typical implementation might consist of 16 or more lines: 8  
16 data, 5 address, and 3 control. Many RF test fixtures such as the TS-50  
17 (Yukon) and the Z2030A (Osprey) use this control method.

18

19 A command serial control method consists of sending commands across the  
20 filtered connector(s) to a microprocessor or other programmable logic device  
21 that can interpret these commands into control sequences. This method  
22 commonly requires a clock to be running at all times inside the RF enclosed  
23 portion for clocking the microprocessor or logic device. This clock creates  
24 spurious noise that can interfere with the measurements inside the RF cavity.  
25 Command serial control methods are also more complicated and often require  
26 some firmware programming.

27

28 Other methods of control across an RF barrier exist that do not use an  
29 electrical connection. An example of this is an optical link. These methods

100010591-1

1 tend to be more expensive and require a free running clock that adds to the  
2 electrical noise inside the RF cavity.

3

4 Thus, there is an unmet need in the art for a simple, cost effective method of  
5 controlling electronics across an RF barrier. Such a method should provide  
6 an ideal environment for test RF devices, have good RF isolation, encompass  
7 a less expensive design with fewer lines and built-in interfaces, have low  
8 spurious noise, be simple to implement, and be flexible and extensible to  
9 future enhancements.

10

11

12 SUMMARY OF THE INVENTION

13

14

15 The present invention takes advantage of the industry standard serial data  
16 control buses capable of serially shifting data in and/or out of electronics  
17 being controlled in some pre-determined protocol to provide a serial data  
18 control protocol for controlling electronics across an RF barrier. A  
19 microprocessor with a built-in serial data control bus (e.g., SPI) exists outside  
20 of the RF chamber. An address dependent form of the serial bus passes  
21 through one or more RF filtered connectors into the RF cavity. The processor  
22 uses the serial data bus to control (data reads and data writes) an arbitrary  
23 amount of electronics inside and outside of the RF cavity. This control  
24 method requires a minimal number of signals passing through the filtered  
25 connectors, preserving the RF isolation of the cavity from the external  
26 environment.

27

28 The addressing scheme is designed to specifically isolate electronics outside  
29 the RF chamber from the electronics inside the chamber. The serial data bus

10010591-1  
10010591-1  
10010591-1  
10010591-1

10010591-1

1 lines that pass through into the RF cavity are held in a quiescent state unless  
2 being used to control electronics inside the RF cavity. This signal isolation  
3 technique provides a very low spurious noise environment inside the RF  
4 cavity. This is important for sensitive RF measurements, while allowing the  
5 processor to control external electronics. This gating functionality may  
6 additionally have a temporal aspect that controls when individual signals are  
7 gated from entering the RF cavity. This provides the important advantage of  
8 being able to selectively control noise levels experienced during the testing  
9 process.

10

11

12                   BRIEF DESCRIPTION OF THE DRAWINGS

13

14 The features of the invention believed to be novel are set forth with  
15 particularity in the appended claims. The invention itself however, both as to  
16 organization and method of operation, together with objects and advantages  
17 thereof, may be best understood by reference to the following detailed  
18 description of the invention, which describes certain exemplary embodiments  
19 of the invention, taken in conjunction with the accompanying drawings in  
20 which:

21

22                   **FIG. 1** is a block diagram of an RF cavity and the associated control  
23 elements, according to an embodiment of the present invention.

24

25                   **FIG. 2** is a sample addressing scheme, according to an embodiment of  
26 the present invention.

27

28

29                   DETAILED DESCRIPTION OF THE INVENTION

1

2 While this invention is susceptible of embodiment in many different forms,  
3 there is shown in the drawings and will herein be described in detail specific  
4 embodiments, with the understanding that the present disclosure is to be  
5 considered as an example of the principles of the invention and not intended  
6 to limit the invention to the specific embodiments shown and described. In the  
7 description below, like reference numerals are used to describe the same,  
8 similar or corresponding parts in the several views of the drawings.

9

10 A number of industry standard serial data control buses exist for controlling  
11 electronics using a limited number of electrical lines. These buses serially  
12 shift data in and/or out of electronics being controlled in some pre-determined  
13 protocol. These buses commonly require a clock line, data line, and possibly  
14 one or more control lines. Such control lines may be used for operations such  
15 as chip select and chip reset, depending upon the exact bus implementation.  
16 Examples of these protocols include Microwire, I2C, SPI, and JTAG Boundary  
17 Scan (IEEE1149.1). Industry standard buses are commonly available on  
18 many different types of electronics including microprocessors, Digital-to-  
19 Analog Converters (DACs), Analog-to-Digital Converters (ADCs), memories,  
20 and register-based control devices.

21

22 The present invention is able to use these serial data control buses to provide  
23 a serial data control protocol for controlling electronics across an RF barrier.  
24 A microprocessor with a built-in serial data control bus (e.g., SPI) exists  
25 outside of the RF chamber. An address dependent form of the serial bus  
26 passes through one or more RF filtered connectors into the RF cavity. The  
27 processor uses the serial data bus to control (data reads and data writes) an  
28 arbitrary amount of electronics inside and outside of the RF cavity. This  
29 control method requires a minimal number of signals passing through the

1 filtered connectors, preserving the RF isolation of the cavity from the external  
2 environment.

3

4 Referring to block diagram 100 of **Figure 1**, an embodiment of the present  
5 invention is shown. Processor 120 is coupled to interface electronics 133 via  
6 a serial data control bus cable 125. A non-RF cavity 150 is used to house the  
7 processor 120 and the electronics outside the RF chamber 160. An external  
8 controller 170, such as a personal computer (PC), uses a number of external  
9 interfaces 165, either serial or parallel, e.g. RS232, to control the processor  
10 120. Interface electronics 133 is operable to choose one or more of a  
11 plethora of input signals. The selected input signals are coupled to filtered  
12 connector 130. Filtered connector 130 is coupled to electronics 140 within RF  
13 cavity 110 by serial data control bus cable 135, which may be physically  
14 realized as one or more cables or printed circuit assemblies. Processor 120  
15 is operable to transmit and receive one or more data signals using serial data  
16 control bus cable 125 to filtered connector 130. Filtered connector 130  
17 isolates these one or more data signals and passes them to electronics 140  
18 via serial data control bus cable 135. An addressing scheme is implemented  
19 by processor 120 so that only those serial bus lines that are used to control  
20 electronics 140 within RF cavity 110 are active. The selection of the one or  
21 more serial lines operable to enter RF cavity 110 is controlled by interface  
22 electronics 133. The use of a gating functionality to determine which signals  
23 are permitted to enter RF cavity 110 may additionally have a temporal aspect  
24 in that it may be used to selectively determine when such signals are  
25 permitted to enter RF cavity 110. This temporal aspect is an important  
26 advantage of the present invention. There may be times during the testing  
27 process when eliminating spurious noise is not important but other times,  
28 such as during noise sensitive measurements, which it can be critical.

29

1 Referring now to **Figure 2**, an example of this addressing scheme is shown  
2 according to one embodiment of the present invention. This example uses  
3 eight addresses to control electronics internal and external to the RF cavity.  
4 Addresses 0,1,2, and 3 are operable to control one or more electronics  
5 elements within electronics 140. Addresses 4, 5, 6, and 7 are operable to  
6 control one or more elements within electronics outside the RF chamber 160.  
7 In this example address line #1 is used to gate all signals that enter RF cavity  
8 110. Thus only addresses 0, 1, 2, and 3 are active within the RF cavity. This  
9 gating functionality, enabled through setting the value of line #1, allows a  
10 processor element to allow only those signals used to control electronics 140  
11 enter the RF cavity. Those signals corresponding to addresses 4, 5, 6, and 7  
12 are held in a quiescent mode within the RF cavity. Again, the gating  
13 functionality may have a temporal characteristic in that interface electronics  
14 133 can through the gating control when certain signals are allowed to enter  
15 RF cavity 110.

16

17 Those of ordinary skill in the art will recognize that the present invention has  
18 been described in terms of exemplary embodiments. It should be apparent to  
19 one of skill in the art that the number of addresses and the method of gating  
20 the addresses may differ from that presented in Figure 2. For example, 32  
21 addresses could be used, with 24 applied to components within the cavity and  
22 8 applied to components external to the cavity. In a preferred embodiment of  
23 the present invention, integrated circuit technology is used to provide the  
24 quiescent gating function that allows only certain signals to enter the RF  
25 cavity. This gating function may have a selective temporal quality that  
26 determines when these certain signals are permitted to enter the RF cavity. It  
27 should also be apparent to one of skill in the art that many different types of  
28 serial data control buses could be implemented without departing from the  
29 spirit and scope of the present invention. Microwire, I2C, SPI, and

1 IEEE1149.1 are some examples of applicable serial data control buses.  
2 According to the preferred embodiment of the present invention, SPI is used  
3 as the serial data control bus.

4

5 It should also be apparent to one or skill in the art that interface electronics  
6 133 is operable to be coupled directly to processor 120 without departing from  
7 the spirit and scope of the present invention. Further, electronics component  
8 140 may be distributed in several locations within RF enclosure 110. Filtered  
9 connector 130 is operable to maintain connections with one or more of these  
10 distributed electronics components.

11

12 While the invention has been described in conjunction with specific  
13 embodiments, it is evident that many alternatives, modifications, permutations  
14 and variations will become apparent to those of ordinary skill in the art in light  
15 of the foregoing description. Accordingly, it is intended that the present  
16 invention embrace all such alternatives, modifications and variations as fall  
17 within the scope of the appended claims.

18

19 What is claimed is:

20

21